

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/670,354	NIWA, TAKEO	
	Examiner Stephen J Stein	Art Unit 1775	Page 1 of 1

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	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
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	L	US-			
	M	US-			

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